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FIG.1 (PRIOR ART)

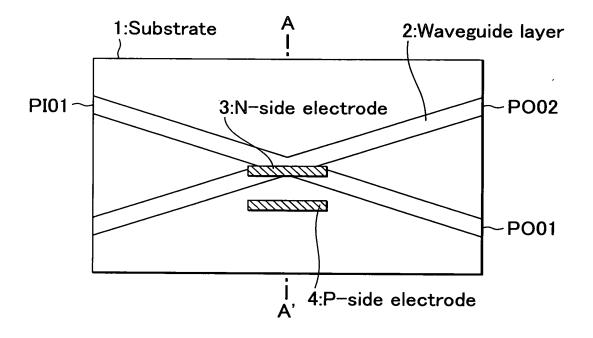
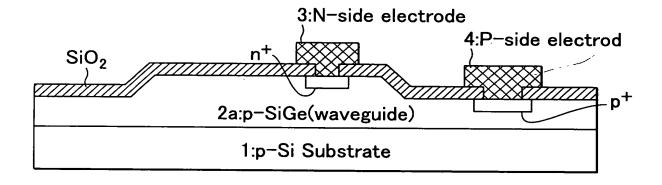


FIG.2 (PRIOR ART)



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FIG.3 (PRIOR ART)

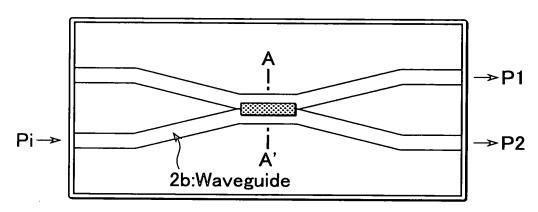
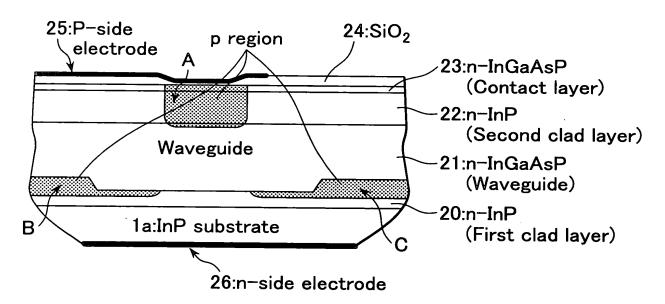


FIG.4 (PRIOR ART)



9c:Polyimide layer

9b:Polyimide layer

6:Clad layer

9a:Polyimide layer

5:Contact layer

1:Substrate

10b:Wiring pattern 4:P-side electrode 7:Cap layer n⁺-GaAs 3:N-side electrode p⁺-GaAs GaAs FIG.5 n⁻-GaAs 2:Waveguide layer P-AlGaAs 10a:Wiring pattern 8:Insulation film



FIG.6

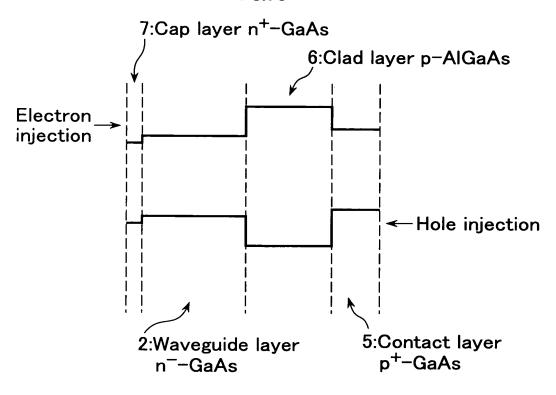
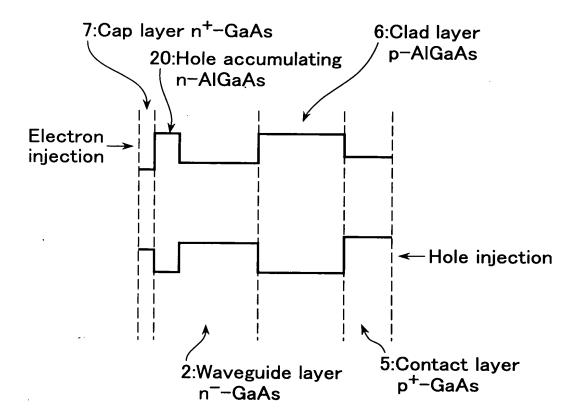


FIG.7



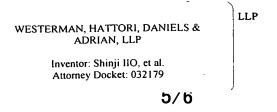


FIG.8

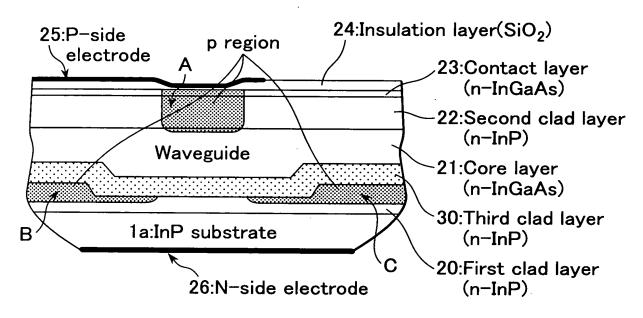


FIG.9

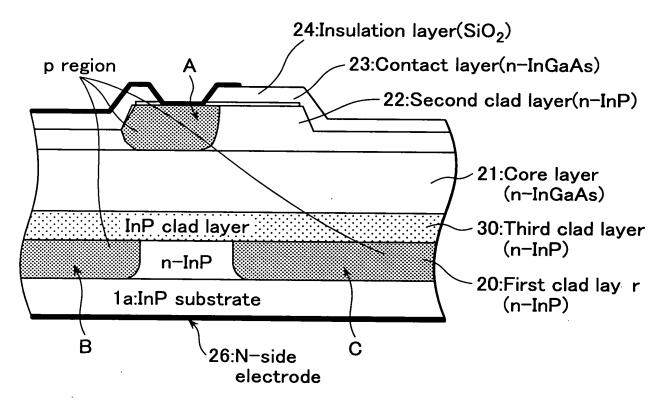




FIG.10

Index distribution

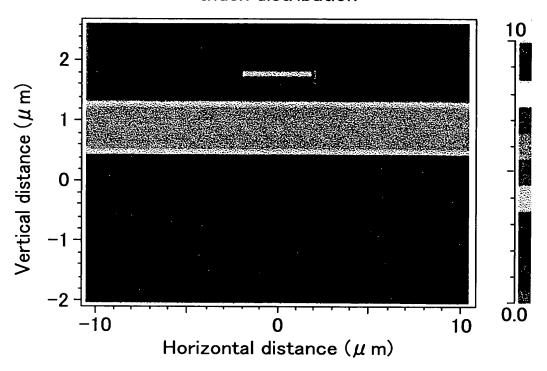


FIG.11
Intensity distribution

